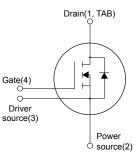


## N-channel 650 V, 19.9 mΩ typ., 92 A MDmesh M9 Power MOSFET in a TO247-4 package





# ND1TPS2DS3G4



# **Product status link** STW65N023M9-4

Product summary			
Order code	STW65N023M9-4		
Marking	65N023M9		
Package	TO247-4		
Packing	Tube		

#### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STW65N023M9-4	650 V	23.0 mΩ	92

- Worldwide best FOM  $R_{DS(on)}^*Q_g$  among silicon-based devices
- Higher V<sub>DSS</sub> rating
- Higher dv/dt capability
- Excellent switching performance thanks to the extra driving source pin
- Easy to drive
- 100% avalanche tested

#### **Applications**

High efficiency switching applications

#### **Description**

This N-channel Power MOSFET is based on the most innovative super-junction MDmesh M9 technology, suitable for medium/high voltage MOSFETs featuring very low  $R_{DS(on)}$  per area. The silicon based M9 technology benefits from a multi-drain manufacturing process which allows an enhanced device structure. The resulting product has one of the lower on-resistance and reduced gate charge values, among all silicon based fast switching super-junction Power MOSFETs, making it particularly suitable for applications that require superior power density and outstanding efficiency.



# 1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	±30	V
I-	Drain current (continuous) at T <sub>C</sub> = 25 °C	92	
Ι <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100 °C	58	_ A
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	440	Α
P <sub>TOT</sub>	Total power dissipation at T <sub>C</sub> = 25 °C	463	W
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope	50	V/ns
di/dt <sup>(2)</sup>	Peak diode recovery current slope	850	A/µs
dv/dt <sup>(3)</sup>	MOSFET dv/dt ruggedness	120	V/ns
T <sub>stg</sub>	Storage temperature range	EE to 150	°C
T <sub>J</sub>	Operating junction temperature range	-55 to 150	°C

- 1. Pulse width is limited by safe operating area.
- 2.  $I_{SD} \le 48~A,~V_{DS}~(peak) < V_{(BR)DSS},~V_{DD} = 400~V.$
- 3.  $V_{DS}$  (peak)  $< V_{(BR)DSS}$ ,  $V_{DD} = 400 V$ .

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R <sub>thJC</sub>	Thermal resistance, junction-to-case	0.27	°C/W
R <sub>thJA</sub>	Thermal resistance, junction-to-ambient	50	°C/W

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or non-repetitive (pulse width limited by T <sub>J</sub> max.)	12	A
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_J = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	1307	mJ

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## 2 Electrical characteristics

 $T_C$  = 25 °C unless otherwise specified.

Table 4. On-/off-states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	650			V
lana	Zero gate voltage drain current	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 650 V			1	μA
I <sub>DSS</sub>		$V_{GS}$ = 0 V, $V_{DS}$ = 650 V, $T_{C}$ = 125 °C <sup>(1)</sup>			200	
I <sub>GSS</sub>	Gate-body leakage current	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = ±25 V			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_{D} = 250 \mu A$	3.2	3.7	4.2	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 48 A		19.9	23.0	mΩ

<sup>1.</sup> Specified by design, not tested in production.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance	V <sub>DS</sub> = 400 V, f = 1 MHz, V <sub>GS</sub> = 0 V	-	8844	-	pF
C <sub>oss</sub>	Output capacitance	VDS - 400 V, I - I WIIIZ, VGS - 0 V	-	140	-	pF
Coss eq. (1)	Equivalent output capacitance	V <sub>DS</sub> = 0 to 400 V, V <sub>GS</sub> = 0 V	-	1750	-	pF
R <sub>G</sub>	Intrinsic gate resistance	f = 1 MHz, open drain	-	0.8	-	Ω
Qg	Total gate charge	V <sub>DD</sub> = 400 V, I <sub>D</sub> = 48 A, V <sub>GS</sub> = 0 to 10 V	-	230	-	nC
Q <sub>gs</sub>	Gate-source charge	(see Figure 14. Test circuit for gate charge behavior).	-	52	-	nC
Q <sub>gd</sub>	Gate-drain charge		-	108	-	nC

<sup>1.</sup>  $C_{\text{oss eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{\text{oss}}$  when  $V_{DS}$  increases from 0 to stated value.

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	V <sub>DD</sub> = 325 V, I <sub>D</sub> = 48 A,	-	45	-	ns
t <sub>r</sub>	Rise time	$R_G$ = 4.7 $\Omega$ , $V_{GS}$ = 10 $V$ (see Figure 13. Switching times test circuit for resistive load and Figure 18. Switching time waveform)	-	15	-	ns
t <sub>d(off)</sub>	Turn-off delay time		-	145	-	ns
t <sub>f</sub>	Fall time		-	7	-	ns

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Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		92	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		440	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 95 A, V <sub>GS</sub> = 0 V	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 95 A, di/dt = 100 A/μs,	-	330		ns
Qrr	Reverse recovery charge	V <sub>DD</sub> = 100 V	-	5.45		μC
I <sub>RRM</sub>	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	30		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 95 A, di/dt = 100 A/μs,	-	465		ns
Q <sub>rr</sub>	Reverse recovery charge	V <sub>DD</sub> = 100 V, T <sub>J</sub> = 150 °C	-	10.85		μC
I <sub>RRM</sub>	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	34		Α

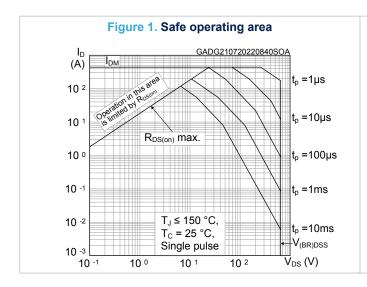
<sup>1.</sup> Pulse width is limited by safe operating area.

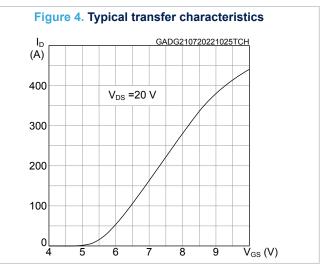
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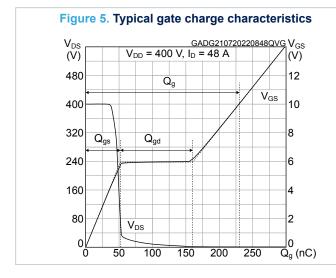
<sup>2.</sup> Pulsed: pulse duration = 300  $\mu$ s, duty cycle 1.5%.

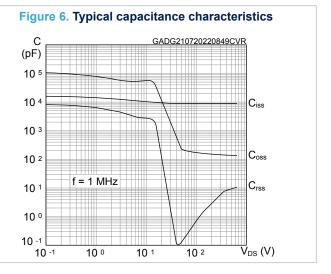


#### 2.1 Electrical characteristics (curves)









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Figure 7. Typical drain-source on-resistance

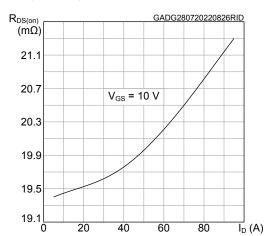


Figure 8. Normalized on-resistance vs temperature

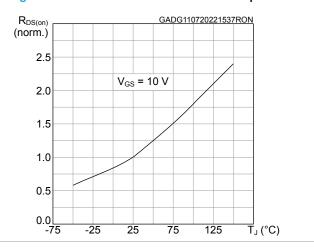


Figure 9. Normalized gate threshold vs temperature

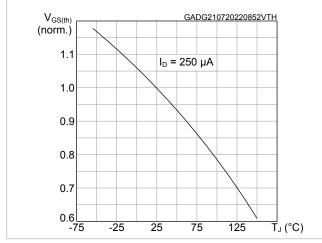


Figure 10. Normalized breakdown voltage vs temperature

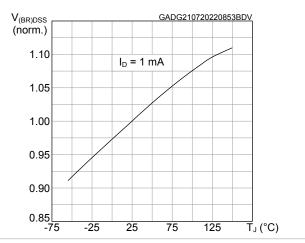


Figure 11. Typical reverse diode forward characteristics

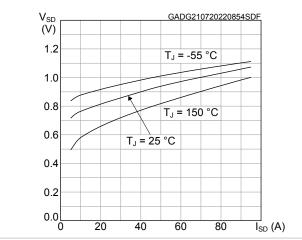
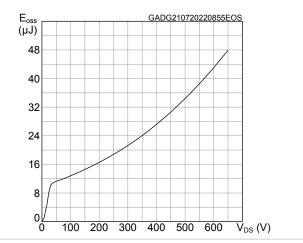


Figure 12. Typical output capacitance stored energy



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#### 3 Test circuits

Figure 13. Switching times test circuit for resistive load

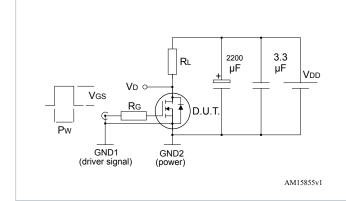


Figure 14. Test circuit for gate charge behavior

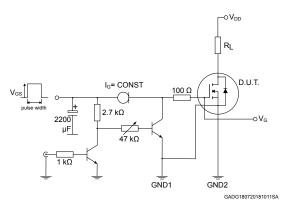


Figure 15. Test circuit for inductive load switching and diode recovery times

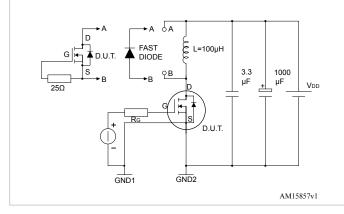


Figure 16. Unclamped inductive load test circuit

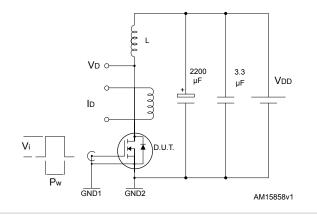


Figure 17. Unclamped inductive waveform

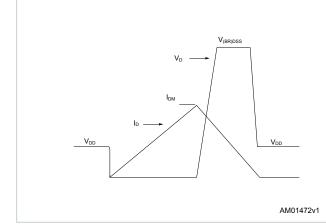
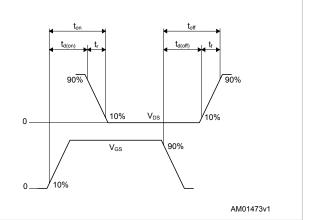


Figure 18. Switching time waveform



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# 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

## 4.1 TO247-4 package information

Α2  $\Box$ D3 øP2 E1 Α1 b2 b (x4) e(x2)SECTION A-A BASE METAL WITH PLATING b1

Figure 19. TO247-4 package outline

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Table 8. TO247-4 mechanical data

Dim.		mm	
Dim.	Min.	Тур.	Max.
А	4.90	5.00	5.10
A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
b	1.16		1.29
b1	1.15	1.20	1.25
b2	0		0.20
С	0.59		0.66
c1	0.58	0.60	0.62
D	20.90	21.00	21.10
D1	16.25	16.55	16.85
D2	1.05	1.20	1.35
D3	24.97	25.12	25.27
E	15.70	15.80	15.90
E1	13.10	13.30	13.50
E2	4.90	5.00	5.10
E3	2.40	2.50	2.60
е	2.44	2.54	2.64
e1	4.98	5.08	5.18
L	19.80	19.92	20.10
Р	3.50	3.60	3.70
P1			7.40
P2	2.40	2.50	2.60
Q	5.60		6.00
S		6.15	
Т	9.80		10.20
U	6.00		6.40
aaa		0.04	0.10

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# **Revision history**

Table 9. Document revision history

Date	Revision	Changes
02-Dec-2022	1	First release.
01-Mar-2023	2	Updated Table 4. On-/off-states.
	3	Updated title and Features in cover page.
17-Jul-2023		Updated Table 1. Absolute maximum ratings.
17-Jul-2023		Updated Table 6. Switching times and Table 7. Source-drain diode.
		Updated Section 3 Test circuits.

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